



IN-SITU REAL-TIME MONITORING TECHNIQUE AND APPARATUS FOR DETECTION
OF THIN FILMS DURING CHEMICAL/MECHANICAL POLISHING PLANARIZATION
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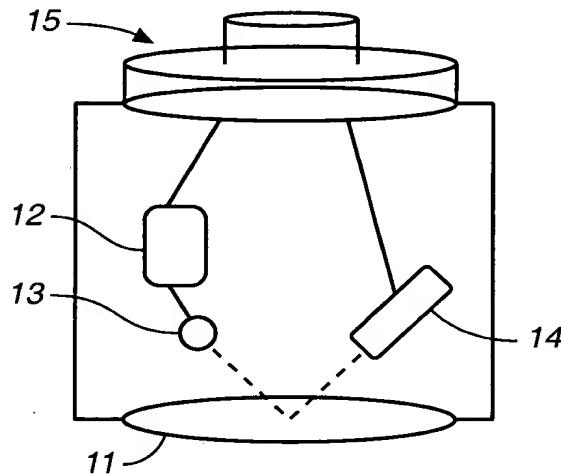


FIG._5

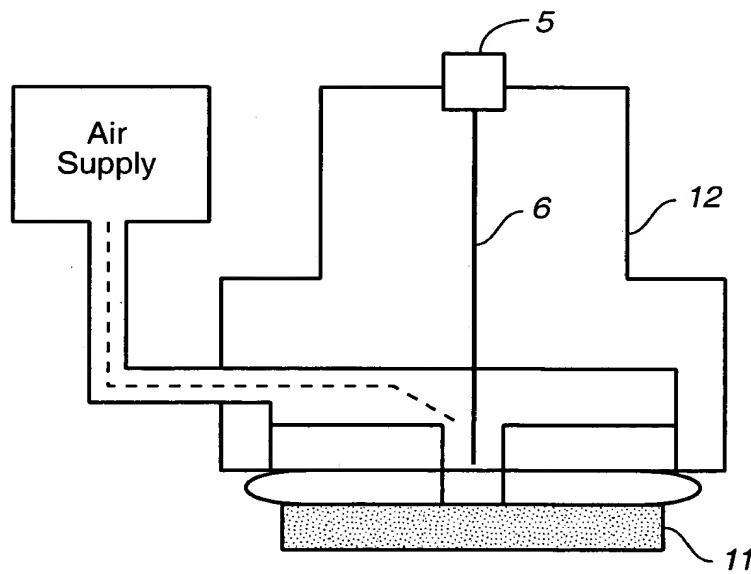


FIG._6



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